

CELEBRATING 70 YEARS

JEOL is a world-leading provider of instrumentation and solutions for advanced scientific and industrial research and development.

2019

JEOL celebrates its 70th anniversary, introducing the new GC/Triple Quadrupole mass spec with high speed and sensitivity. JEOL releases information about MARS, the first atomic resolution microscope with a field free sample area.



2017

JEOL introduces HFX NMR Probe for fluorinated compounds.

2012

JEOL introduces new Field Emission SEM series with sub-1 nm imaging capabilities.

2008

JEOL introduces benchtop SEM with LV and high resolution.

2005

DART revolutionizes mass spec and appears on popular crime television show, CSI. It wins US Patent award, Pittcon Editors' Gold Award, and the R&D 100 Award.

2002

The new generation of NMR spectrometers, ECA/ECX, is introduced.

1999

JEOL Ltd. celebrates 50th anniversary.

1964

First JEOL mass spectrometer, JMS-01, introduced.



1956

The first JEOL NMR, JNM-1, was introduced.



2018

JEOL launches new Monochromated Atomic Resolution (ARM200F) TEM.



2016

50th anniversary of first JEOL SEM. JEOL founders were recognized with the Pittcon Heritage Award.

2011

R&D 100 Award goes to InTouchScope (JSM-6010) SEM.



2006

New ultra-high resolution FE SEM achieves true 1,000,000X imaging.

2003

Automated structural elucidation software for NMR was introduced.

2001

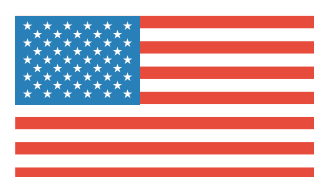
The world's first NMR spectrometer supporting 10 RF channels is introduced.

1965-1989

First JEOL SPM, e-beam lithography, and STM all introduced to market. In 1985, JEOL developed the world's first auto-tunable NMR probe. In 1966, the JEM-1000 Ultrahigh Voltage (1000kV) Electron Microscope completed.

1962

JEOL USA, Inc. was incorporated into the United States and established as the first overseas subsidiary.



1949

Japan Electron Optics Laboratory Co., Ltd. established in Tokyo, and the JEM-1 electron microscope was completed.

70TH
ANNIVERSARY

Visit www.jeolusa.com for more information.